Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/692,800	MIYAKE ET AL.
Examiner	Art Unit
Benjamin P. Geib	2181

SEARCHED			
Class	Subclass	Date	Examiner
717	129	2/8/2006	BPG
712	244	2/9/2006	BPG

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
-			

SEARCH (INCLUDING SEA	NOTES RCH STRATEC	GY)
	DATE	EXMR
East Search	2/8/2006	6 BPG
IEEE Xplore Search	2/8/2006	BPG
ACM Search	2/8/2006	BPG
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